

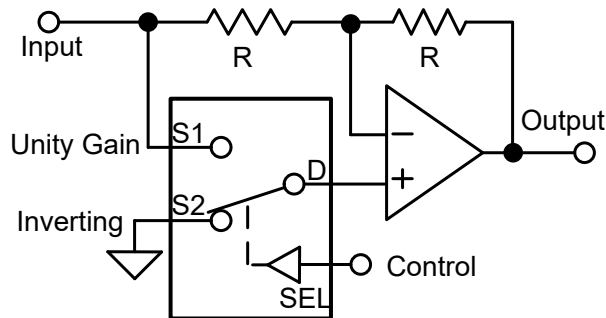
SN4599-Q1 Automotive 5V, 2:1 (SPDT), 1-Channel Analog Switch

1 Features

- AEC-Q100 qualified for automotive applications:
 - Device temperature grade 1: -40°C to 125°C ambient operating temperature
 - Device HBM classification level H1C
 - Device CDM classification level C3
- [Rail to rail operation](#)
- [Bidirectional signal path](#)
- Low on-resistance: 7Ω
- Wide supply range: 2V to 5.5V
- -40°C to $+125^{\circ}\text{C}$ Operating temperature
- Break-before-make switching
- SN4599-Q1 a direct replacement for NLAS4599-Q1

2 Applications

- Analog and digital switching
- I2C and SPI bus multiplexing
- [Advanced driver assistance systems \(ADAS\)](#)
- [Body electronics and lighting](#)
- [Infotainment and cluster](#)
- Zonal architecture
- [Body control modules](#)
- [Battery management systems](#)
- [Telematics](#)
- [Automotive head unit](#)



Application Example

3 Description

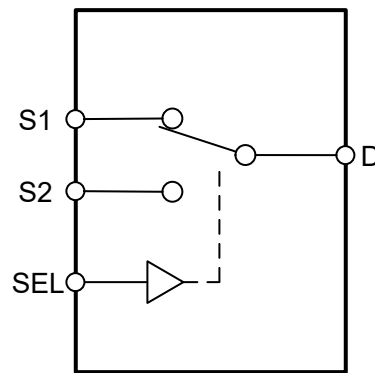
The SN4599-Q1 is a general purpose complementary metal-oxide semiconductor (CMOS) single-pole double-throw (SPDT) switch. The SN4599-Q1 switches between two source inputs based on the state of the SEL pin. Wide operating supply of 2V to 5.5V allows for use in a broad array of automotive applications. The device supports bidirectional analog and digital signals on the source (Sx) and drain (D) pins ranging from GND to V_{DD} .

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾
SN4599-Q1	DBV (SOT-23, 6)	2.9mm × 2.8mm

(1) For more information, see [Section 11](#)

(2) The package size (length × width) is a nominal value and includes pins, where applicable.



Block Diagram



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4 Pin Configuration and Functions

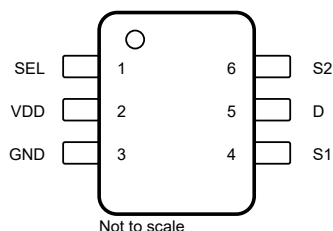


Figure 4-1. DBV Package 6-Pin SOT-23 (Top View)

Table 4-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.		
SEL	1	I	Select pin: controls state of the switch according to Table 7-1 . (Logic Low = S1 to D, Logic High = S2 to D)
VDD	2	P	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1μF to 10μF between V _{DD} and GND.
GND	3	P	Ground (0V) reference
S1	4	I/O	Source pin 1. Can be an input or output.
D	5	I/O	Drain pin. Can be an input or output.
S2	6	I/O	Source pin 2. Can be an input or output.

(1) I = input, O = output, I/O = input and output, P = power

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V_{DD}	Supply voltage	-0.5	6	V
V_{IN}	Control input voltage ⁽²⁾	-0.5	6	V
$V_{I/O}$	Voltage range applied to any output in the high-impedance or power-off state ^{(2) (3)}	-0.5	$V_{DD} + 0.5$	V
I_{IK}	Control input clamp current $V_{IN} < 0$		-50	mA
$I_{I/O}$	I/O port diode current $V_{I/O} < 0$ or $V_{I/O} > V_{DD}$	-50	50	mA
$I_{I/O}$	On-state switch current ⁽⁴⁾ $V_{I/O} = 0$ to V_{DD}	$I_{DC} \pm 10\%$ ⁽⁷⁾	$I_{DC} \pm 10\%$ ⁽⁷⁾	mA
P_{tot}	Total power dissipation		300	mW
T_J	Junction temperature		150	°C
Storage temperature, T_{stg}		-65	150	°C

- (1) Operation outside the Absolute Maximum Rating may cause permanent device damage. Absolute Maximum Rating do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Condition. If used outside the Recommended Operating Condition but within the Absolute Maximum Rating, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) All voltages are with respect to ground unless otherwise specified.
- (3) V_I , V_O , V_A , and V_{Bn} are used to denote specific conditions for $V_{I/O}$.
- (4) I_I , I_O , I_A , and I_{Bn} are used to denote specific conditions for $I_{I/O}$.
- (5) Refer to *Source or Drain Current* table for I_{DC} specifications.

5.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per AEC Q100-002 ⁽¹⁾	±2000	V
		Charged device model (CDM), per AEC Q100-011	±750	

- (1) AEC Q100-002 indicates that HBM stressing must be in accordance with the ANSI/ESDA/JEDEC JS-002 specification.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
V _{DD}	Supply voltage		2		5.5	V
V _{I/O}	Switch input or output voltage (Max of V _{DD})		0		V _{DD}	V
V _{IN}	Control input voltage		0		5.5	V
V _{IH}	High-level input voltage	V _{DD} = 2V to 2.29V	V _{DD} x 0.75			V
		V _{DD} = 2.3V to 5.5V	V _{DD} x 0.7			
V _{IL}	Low-level input voltage	V _{DD} = 2V to 2.29V	V _{DD} x 0.25			V
		V _{DD} = 2.3V to 2.9V	V _{DD} x 0.3			
		V _{DD} = 3V to 5V	0.85			

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		SN4599-Q1	UNIT
		DBV (SOT-23)	
		6 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	212.3	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	156.7	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	96.5	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	80.7	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	96.	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

5.5 Source or Drain Current through Switch

Current through the Switch	$T_J = 25^{\circ}\text{C}$	$T_J = 85^{\circ}\text{C}$	$T_J = 125^{\circ}\text{C}$	$T_J = 130^{\circ}\text{C}$	UNIT
I_{DC} ⁽¹⁾	150	120	60	50	mA
I_{peak} ⁽²⁾	300	300	180	160	mA

- (1) See **Thermal Considerations** section for more details
 (2) Pulse current of 1ms with 10% Duty Cycle

5.6 Electrical Characteristics

Over operating free-air temperature range, $V_{\text{SUPPLY}} = \pm 5 \text{ V}$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS				MIN	TYP	MAX	UNIT
SN4599-Q1									
		V _{DD} V	V _{I/O} V	I _O mA	T _A				
r _{ON}	ON-state switch resistance	2 V	V _I = 0 V	I _O = 4 mA	25°C			11	Ω
					–40°C to +85°C			20	
					–40°C to +125°C			20	
			V _I = 1.65	I _O = -4 mA	25°C			15	
					–40°C to +85°C			50	
					–40°C to +125°C			50	
		2.3 V	V _I = 0 V	I _O = 8 mA	25°C			8	
					–40°C to +85°C			12	
					–40°C to +125°C			12	
			V _I = 2.3 V	I _O = -8 mA	25°C			11	
					–40°C to +85°C			30	
					–40°C to +125°C			30	
		3 V	V _I = 0 V	I _O = 24 mA	25°C			7	
					–40°C to +85°C			9	
					–40°C to +125°C			9	
			V _I = 3 V	I _O = -24 mA	25°C			9	
					–40°C to +85°C			20	
					–40°C to +125°C			20	
		4.5 V	V _I = 0 V	I _O = 30 mA	25°C			6	
					–40°C to +85°C			7	
					–40°C to +125°C			7	
			V _I = 2.4 V	I _O = 30 mA	25°C			7	
					–40°C to +85°C			12	
					–40°C to +125°C			12	
			V _I = 4.5 V	I _O = -30 mA	25°C			7	
					–40°C to +85°C			15	
					–40°C to +125°C			15	
r _{range}	ON-state switch resistance over signal range	2 V	0 ≤ V _{Sn} ≤ V _{DD}	I _D = -4 mA	25°C			210	Ω
					–40°C to +85°C			210	
					–40°C to +125°C			210	
		2.3 V		I _D = -8 mA	25°C			85	
					–40°C to +85°C			85	
					–40°C to +125°C			85	
		3 V		I _D = -24 mA	25°C			30	
					–40°C to +85°C			30	
					–40°C to +125°C			30	
		4.5 V		I _D = -30 mA	25°C			18	
					–40°C to +85°C			18	
					–40°C to +125°C			18	

5.6 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5\text{ V}$, and $R_L = 100\ \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS				MIN	TYP	MAX	UNIT	
Δr_{ON}	Maximum ON resistance between any two channels	2 V	$V_{Sn} = 1.15\text{ V}$	$I_D = -4\text{ mA}$	25°C	0.5			Ω	
					−40°C to +85°C	0.5				
					−40°C to +125°C	0.5				
		2.3 V	$V_{Sn} = 1.6\text{ V}$	$I_D = -8\text{ mA}$	25°C	0.1				
					−40°C to +85°C	0.1				
					−40°C to +125°C	0.3				
		3 V	$V_{Sn} = 2.1\text{ V}$	$I_D = -24\text{ mA}$	25°C	0.1				
					−40°C to +85°C	0.1				
					−40°C to +125°C	0.3				
		4.5 V	$V_{Sn} = 3.15\text{ V}$	$I_D = -30\text{ mA}$	25°C	0.1				
					−40°C to +85°C	0.1				
					−40°C to +125°C	0.2				
$r_{on(Flat)}$	ON resistance flatness	2 V	$0 \leq V_{Sn} \leq V_{DD}$	$I_D = -4\text{ mA}$	25°C	110			Ω	
					−40°C to +85°C	110				
					−40°C to +125°C	110				
		2.3 V		$I_D = -8\text{ mA}$	25°C	26				
					−40°C to +85°C	26				
					−40°C to +125°C	40				
		3 V		$I_D = -24\text{ mA}$	25°C	9				
					−40°C to +85°C	9				
					−40°C to +125°C	10				
		4.5 V		$I_D = -30\text{ mA}$	25°C	4				
					−40°C to +85°C	4				
					−40°C to +125°C	5				
I_{off}	Switch OFF leakage current	2 V	$V_S = 1\text{ V} / 1.62\text{ V}$ $V_D = 1.62\text{ V} / 1\text{ V}$		25°C	± 5			nA	
					−40°C to +85°C	± 25				
					−40°C to +125°C	± 100				
		5.5 V			$V_S = 4.5\text{ V} / 1.5\text{ V}$ $V_D = 1.5\text{ V} / 4.5\text{ V}$	25°C	± 5			
						−40°C to +85°C	± 25			
						−40°C to +125°C	± 100			
$I_{S(on)}$	ON-state switch leakage current	5.5	$V_I = V_{DD}$ or GND, $V_O = \text{Open}$		25°C	± 15			nA	
					−40°C to +85°C	± 50				
					−40°C to +125°C	± 100				
I_{IN}	Control input current	0 V to 5.5 V	$0 \leq V_{IN} \leq V_{DD}$		25°C	± 0.05	± 0.1		μA	
					−40°C to +85°C	± 1				
					−40°C to +125°C	± 1				
I_{DD}	Supply current	5.5 V	$SEL = V_{DD}$ or GND		25°C	1			μA	
					−40°C to +85°C	10				
					−40°C to +125°C	35				
C_I	Control input capacitance	5 V	$SEL (V_{DD}/2)$		25°C	2.7			pF	
					−40°C to +85°C	2.7				
					−40°C to +125°C	2.7				

5.6 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{\text{SUPPLY}} = \pm 5 \text{ V}$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
$C_{\text{io(off)}}$	Switch input/output capacitance	5 V	Sn ($V_{\text{DD}}/2$)	25°C		5.2		pF
				–40°C to +85°C		5.2		
				–40°C to +125°C		5.2		
$C_{\text{io(on)}}$	Switch input/output capacitance	5 V	Sn ($V_{\text{DD}}/2$)	25°C		21		pF
				–40°C to +85°C		21		
				–40°C to +125°C		21		
			D ($V_{\text{DD}}/2$)	25°C		21		
				–40°C to +85°C		21		
				–40°C to +125°C		21		

(1) $T_A = 25^\circ\text{C}$

5.7 Analog Channel Specifications

over operating free-air temperature range (unless otherwise noted)

Parameter	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V_{DD}	MIN	NOM	MAX	UNIT
Frequency response (switch on)	D or Sn	Sn or D	$R_L = 50 \Omega$, $f_{\text{in}} =$ sine wave	2 V		250		MHz
				2.3 V		250		
				3 V		250		
				4.5 V		250		
Crosstalk (between switches)	S1 or S2	S2 or S1	$R_L = 50 \Omega$, $f_{\text{in}} =$ 1MHz sine wave	2 V		–54		dB
				2.3 V		–54		
				3 V		–54		
				4.5 V		–54		
Feed through attenuation (switch off)	D or Sn	Sn or D	$C_L = 5 \text{ pF}$, $R_L = 50 \Omega$, $f_{\text{in}} = 1 \text{ MHz}$ (sine wave)	2 V		–57		dB
				2.3 V		–57		
				3 V		–57		
				4.5 V		–57		
Charge injection	SEL ($V_s = V_{\text{DD}}/2$)	D	$C_L = 0.1 \text{ nF}$, $R_L = 1 \text{ M}\Omega$	3.3 V		3		pC
				5 V		7		
Total harmonic distortion	D or Sn	Sn or D	$V_I = 4.0 \text{ V}_{\text{p-p}}$, $V_{\text{bias}} = V_{\text{DD}}/2$, $R_L = 10 \text{ k}\Omega$, $f_{\text{in}} = 600 \text{ Hz}$ to 20 kHz (sine wave)	4.5 V		0.01		%

5.8 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

Parameter		FROM (INPUT)	TO (OUTPUT)	V _{DD}	MIN	NOM	MAX	UNIT
t _{tran}	R _L = 200Ω, C _L = 15pF, V _S = 1V	D or Sn	Sn or D	2 V ± 0.15 V	28			ns
					44			
					44			
	R _L = 200Ω, C _L = 15pF, V _S = 2V	D or Sn	Sn or D	3.3 V ± 0.3 V	14			ns
					20			
					21			
	R _L = 200Ω, C _L = 15pF, V _S = 3V	D or Sn	Sn or D	5 V ± 0.5 V	12			ns
					18			
					19			
T _{B-M}	Break before make time			2 V ± 0.15 V	0.5			ns
				2.5 V ± 0.2 V	0.5			
				3.3 V ± 0.3 V	0.5			
				5 V ± 0.5 V	0.5			

5.9 Typical Characteristics

at $T_A = 25^\circ\text{C}$, $V_{DD} = 5\text{V}$ (unless otherwise noted)

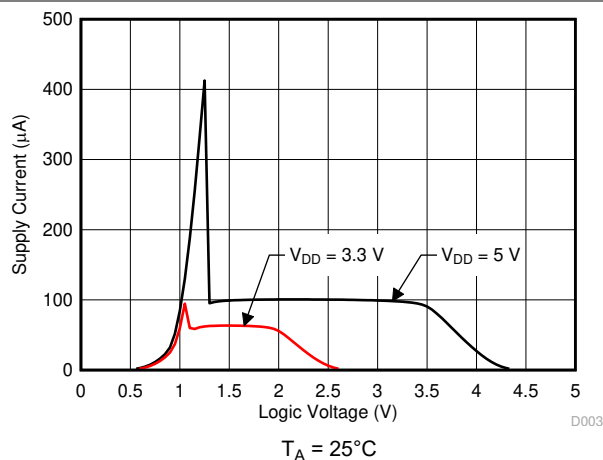


Figure 5-1. Supply Current vs Logic Voltage

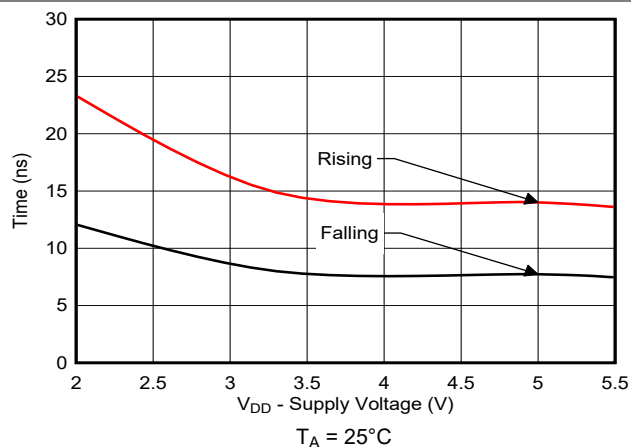


Figure 5-2. $T_{\text{transition}}$ vs Supply Voltage

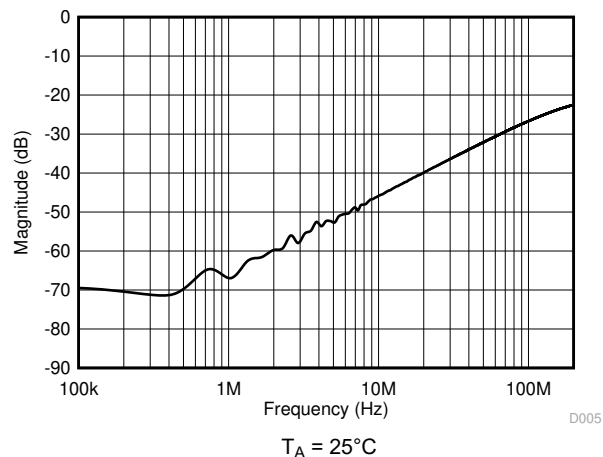


Figure 5-3. Crosstalk and Off-Isolation vs Frequency

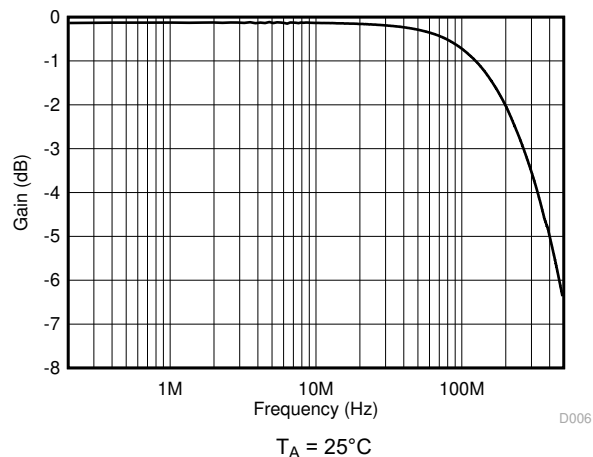


Figure 5-4. Frequency Response

6 Parameter Measurement Information

6.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (D) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote on-resistance. The measurement setup used to measure R_{ON} is shown in Figure 6-1. Voltage (V) and current (I_{SD}) are measured using this setup, and R_{ON} is computed with $R_{ON} = V / I_{SD}$:

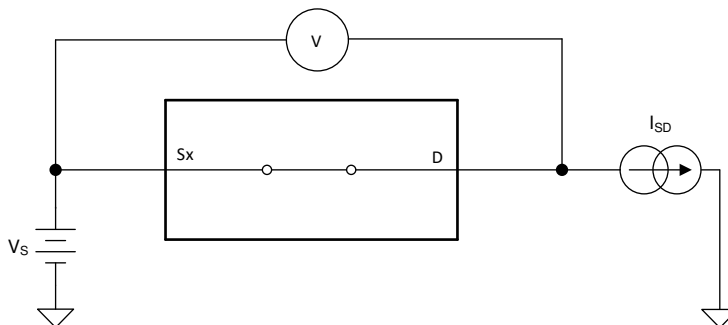


Figure 6-1. On-Resistance Measurement Setup

6.2 Off-Leakage Current

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol $I_{S(OFF)}$.

The setup used to measure off-leakage current is shown in Figure 6-2.

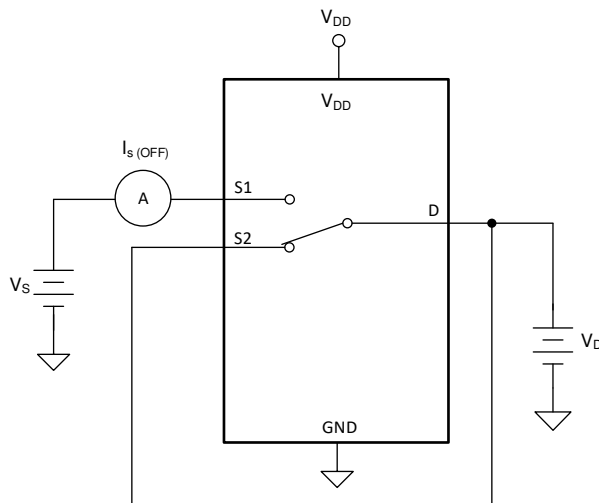


Figure 6-2. Off-Leakage Measurement Setup

6.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol $I_{S(ON)}$.

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol $I_{D(ON)}$.

Either the source pin or drain pin is left floating during the measurement. Figure 6-3 shows the circuit used for measuring the on-leakage current, denoted by $I_{S(ON)}$ or $I_{D(ON)}$.

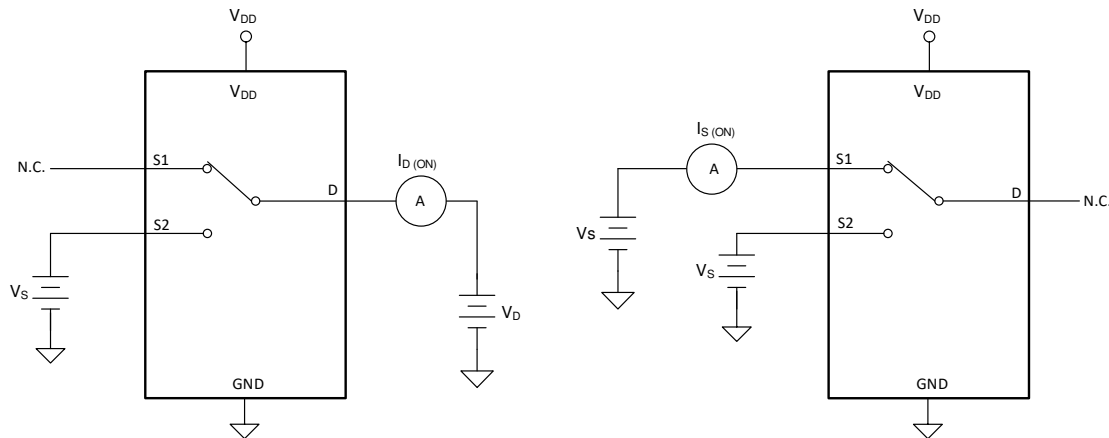


Figure 6-3. On-Leakage Measurement Setup

6.4 Transition Time

Transition time is defined as the time taken by the output of the device to rise or fall 10% after the logic control signal has risen or fallen past the logic threshold. The 10% transition measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. Figure 6-4 shows the setup used to measure transition time, denoted by the symbol $t_{\text{TRANSITION}}$.

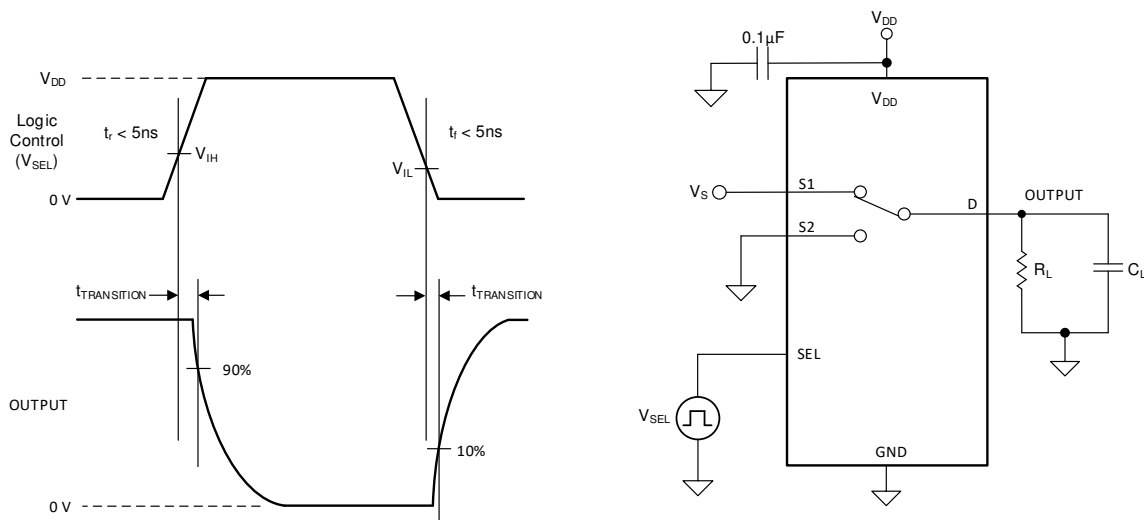


Figure 6-4. Transition-Time Measurement Setup

6.5 Break-Before-Make

Break-before-make delay is a safety feature that prevents two inputs from connecting when the device is switching. The output first breaks from the on-state switch before making the connection with the next on-state switch. The time delay between the *break* and the *make* is known as break-before-make delay. Figure 6-5 shows the setup used to measure break-before-make delay, denoted by the symbol $t_{\text{OPEN(BBM)}}$.

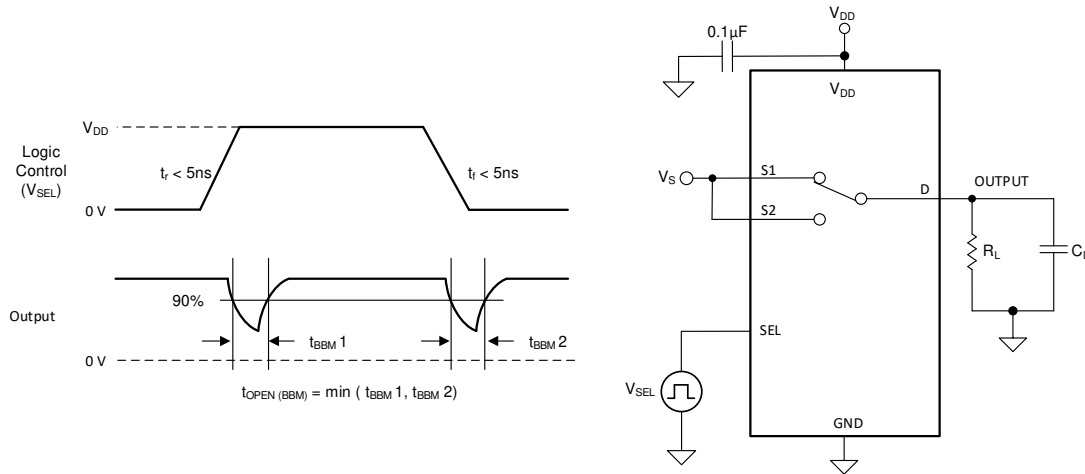


Figure 6-5. Break-Before-Make Delay Measurement Setup

6.6 Charge Injection

The SN4599-Q1 has a transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol Q_C . Figure 6-6 shows the setup used to measure charge injection from Drain (D) to Source (S_x).

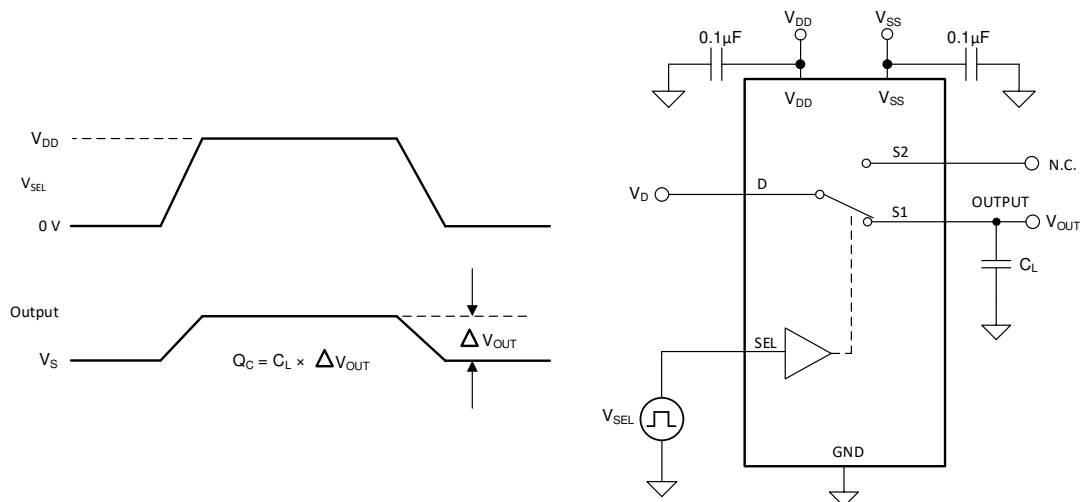


Figure 6-6. Charge-Injection Measurement Setup

6.7 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (D) of the device when a signal is applied to the source pin (S_x) of an off-channel. Figure 6-7 shows the setup used to measure, and the equation used to calculate off isolation.

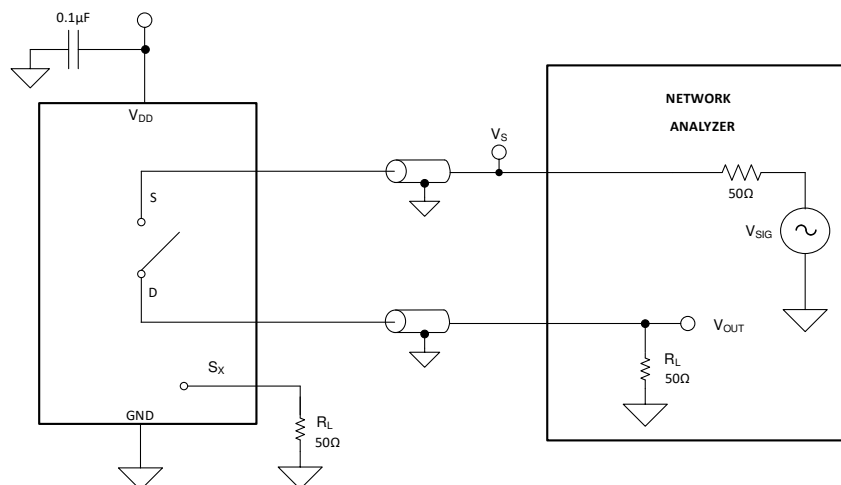


Figure 6-7. Off Isolation Measurement Setup

$$\text{Off Isolation} = 20 \times \text{Log} \left(\frac{V_{OUT}}{V_S} \right) \quad (1)$$

6.8 Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (D) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. [Figure 6-8](#) shows the setup used to measure, and the equation used to calculate crosstalk.

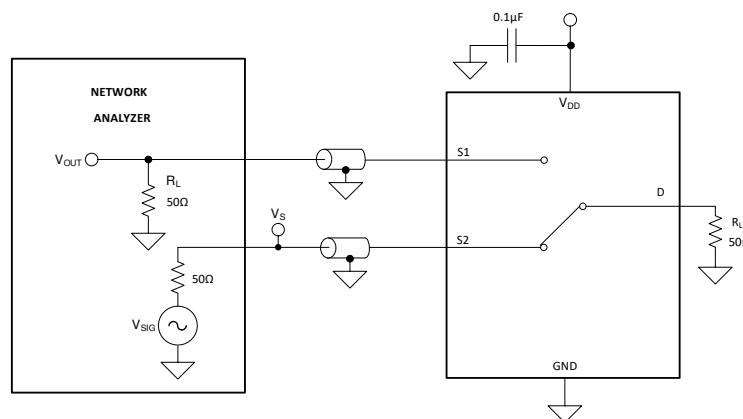


Figure 6-8. Crosstalk Measurement Setup

$$\text{Channel-to-Channel Crosstalk} = 20 \times \text{Log} \left(\frac{V_{OUT}}{V_S} \right) \quad (2)$$

6.9 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (D) of the device. Figure 6-9 shows the setup used to measure bandwidth.

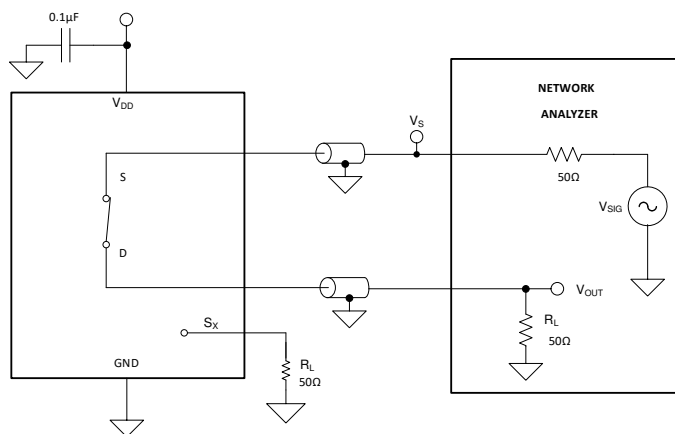


Figure 6-9. Bandwidth Measurement Setup

7 Detailed Description

7.1 Functional Block Diagram

The SN4599-Q1 is an 2:1 (SPDT), 1-channel switch where the input is controlled with a single select (SEL) control pin.

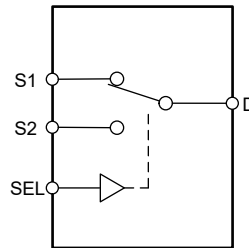


Figure 7-1. SN4599-Q1 Functional Block Diagram

7.2 Feature Description

7.2.1 Bidirectional Operation

The SN4599-Q1 conducts equally well from source (Sx) to drain (D) or from drain (D) to source (Sx). The device has very similar characteristics in both directions and supports both analog and digital signals.

7.2.2 Rail to Rail Operation

The valid signal path input/output voltage for SN4599-Q1 ranges from GND to V_{DD} .

7.2.3 Fail-Safe Logic

The SN4599-Q1 supports Fail-Safe Logic on the control input pin (SEL) allowing for operation up to 5.5V, regardless of the state of the supply pin. This feature allows voltages on the control pin to be applied before the supply pin, protecting the device from potential damage. Fail-Safe Logic minimizes system complexity by removing the need for power supply sequencing on the logic control pins. For example, the Fail-Safe Logic feature allows the select pin of the SN4599-Q1 to be ramped to 5.5V while $V_{DD} = 0V$. Additionally, the feature enables operation of the SN4599-Q1 with $V_{DD} = 2V$ while allowing the select pin to interface with a logic level of another device up to 5.5V.

7.3 Device Functional Modes

The select (SEL) pin of the SN4599-Q1 controls which source channel is connected to the drain of the device. When a signal path is not selected, that source pin is in high impedance mode (HI-Z). The control pin can be as high as 5.5V.

7.4 Truth Tables

Table 7-1. SN4599-Q1 Truth Table

CONTROL LOGIC (SEL)	Selected Source (Sx) Connected To Drain (D) Pin
0	S1
1	S2

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

SN4599-Q1 offers good system performance across a wide operating supply (2V to 5.5V). Additionally, the control input pin supports Fail-Safe Logic which allows for operation up to 5.5V, regardless of the state of the supply pin. This protection stops the logic pins from back-powering the supply rail. These features of the SN4599-Q1 general purpose multiplexer, reduce system complexity, board size, and overall system cost.

8.2 Typical Application

8.2.1 Switchable Operational Amplifier Gain Setting

One example application of the SN4599-Q1 is to change an Op Amp from unity gain setting to an inverting amplifier configuration. Utilizing a switch allows a system to have a configurable gain and allows the same architecture to be utilized across the board for various inputs to the system. Figure 8-1 shows the SN4599-Q1 configured for gain setting application.

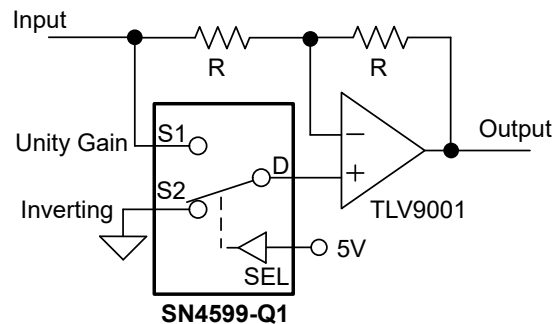


Figure 8-1. Switchable Op Amp Gain Setting

8.2.1.1 Design Requirements

This design example uses the parameters listed in Table 8-1.

Table 8-1. Design Parameters

PARAMETERS	VALUES
Input Signal	0V to 3.3V
Mux Supply (V _{DD})	3.3V
Op Amp Supply (V ₊ / V ₋)	±3.3V
Mux I/O signal range	0V to V _{DD} (Rail to Rail)
Control logic thresholds	2.31V up to 5.5V

8.2.1.2 Detailed Design Procedure

The application shown in Figure 8-1 demonstrates how to use a single control input and toggle between gain settings of -1 and +1. If switching between inverting and unity gain is not required, then the SN4599-Q1 can be utilized in the feedback path to select different feedback resistors and provide scalable gain settings for configurable signal conditioning.

The SN4599-Q1 can operate without any external components except for the supply decoupling capacitors. It is recommended to have a weak pull-down or pull-up resistor so that the input of the select pin is in a known state.

All inputs to the switch must fall within the recommend operating conditions of the SN4599-Q1 including signal range and continuous current. For this design with a supply of 3.3V, the signal range can be 0V to 3.3V and the maximum continuous current can be 30mA.

8.2.1.3 Application Curve

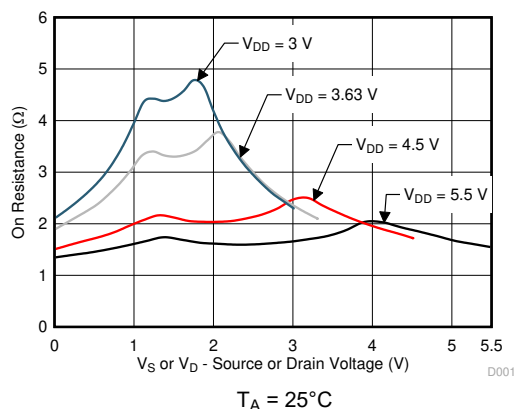


Figure 8-2. On-Resistance vs Source or Drain Voltage

8.2.2 Input Control for Power Amplifier

Another application of the SN4599-Q1 is for input control of a power amplifier. Utilizing a switch allows a system to control when the DAC is connected to the power amplifier, and can stop biasing the power amplifier by switching the gate to GND. Figure 8-3 shows the SN4599-Q1 configured for control of the power amplifier.

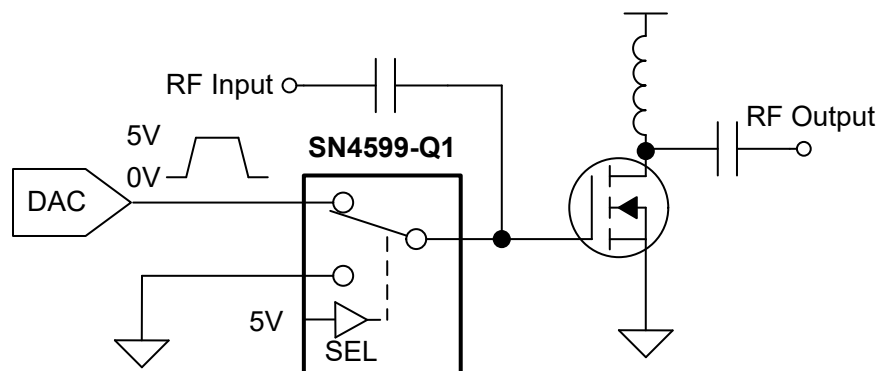


Figure 8-3. Input Control of Power Amplifier

8.2.2.1 Design Requirements

This design example uses the parameters listed in Table 8-1.

Table 8-2. Design Parameters

PARAMETERS	VALUES
Supply (V_{DD})	5V
Mux I/O signal range	0V to V_{DD} (Rail to Rail)
Control logic thresholds	Up to 5.5V

8.2.2.2 Detailed Design Procedure

The application shown in Figure 8-3 demonstrates how to toggle between the DAC output and GND to control a power amplifier using a single control input. The DAC output is utilized to bias the gate of the power amplifier and can be disconnected from the circuit using the select pin of the switch.

The SN4599-Q1 can operate without any external components except for the supply decoupling capacitors. It is recommended to have a weak pull-down or pull-up resistor so that the input of the select pin is in a known state. All inputs to the switch must fall within the recommend operating conditions of the SN4599-Q1 including signal range and continuous current. For this design with a supply of 5V, the signal range can be 0V to 5V and the maximum continuous current can be 30mA.

8.2.2.3 Application Curve

A key parameter for this application is the transition time of the device. Faster transition time allows the system to toggle between input sources at a faster rate and allows the output to settle to the final value. The SN4599-Q1 has a transition time that varies with supply voltage and is shown in [Figure 8-4](#)

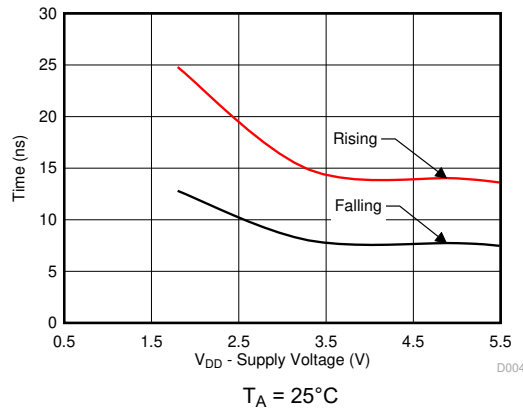


Figure 8-4. $T_{\text{transition}}$ vs Supply Voltage

8.3 Power Supply Recommendations

The SN4599-Q1 operates across a wide supply range of 2V to 5.5V. Do not exceed the absolute maximum ratings because stresses beyond the listed ratings can cause permanent damage to the devices.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the V_{DD} supply to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1 μ F to 10 μ F from V_{DD} to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground planes.

8.4 Layout

8.4.1 Layout Guidelines

When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self-inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. [Figure 8-5](#) shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

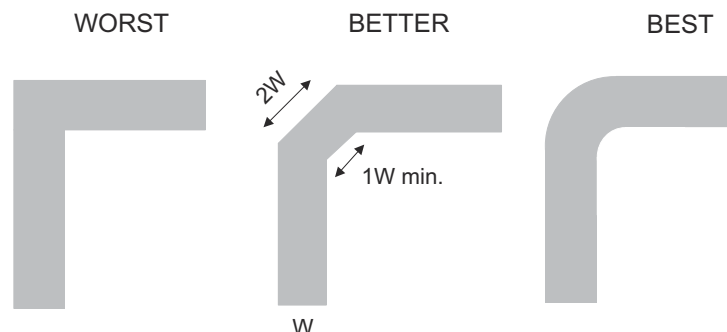


Figure 8-5. Trace Example

Route high-speed signals using a minimum of vias and corners which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points, through-hole pins are not recommended at high frequencies.

Figure 8-6 shows an example of a PCB layout with the SN4599-Q1. Some key considerations are:

- Decouple the V_{DD} pin with a 0.1 μF capacitor, placed as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the V_{DD} supply.
- Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.

8.4.2 Layout Example

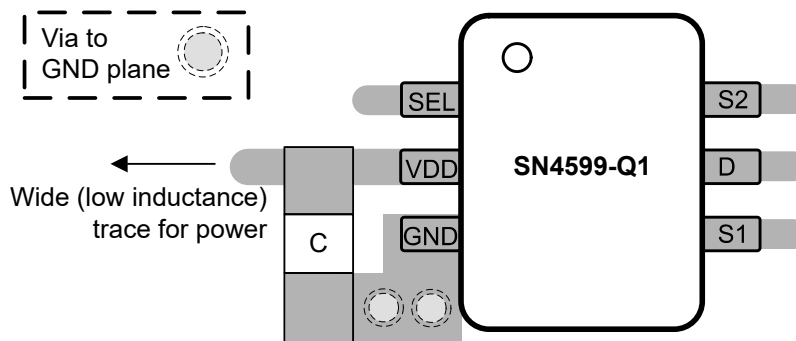


Figure 8-6. SN4599-Q1 Layout Example

9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, [Improve Stability Issues with Low CON Multiplexers](#).
- Texas Instruments, [Eliminate Power Sequencing with Powered-off Protection Signal Switches](#).
- Texas Instruments, [System-Level Protection for High-Voltage Analog Multiplexers](#).

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](https://www.ti.com). Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.4 Trademarks

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

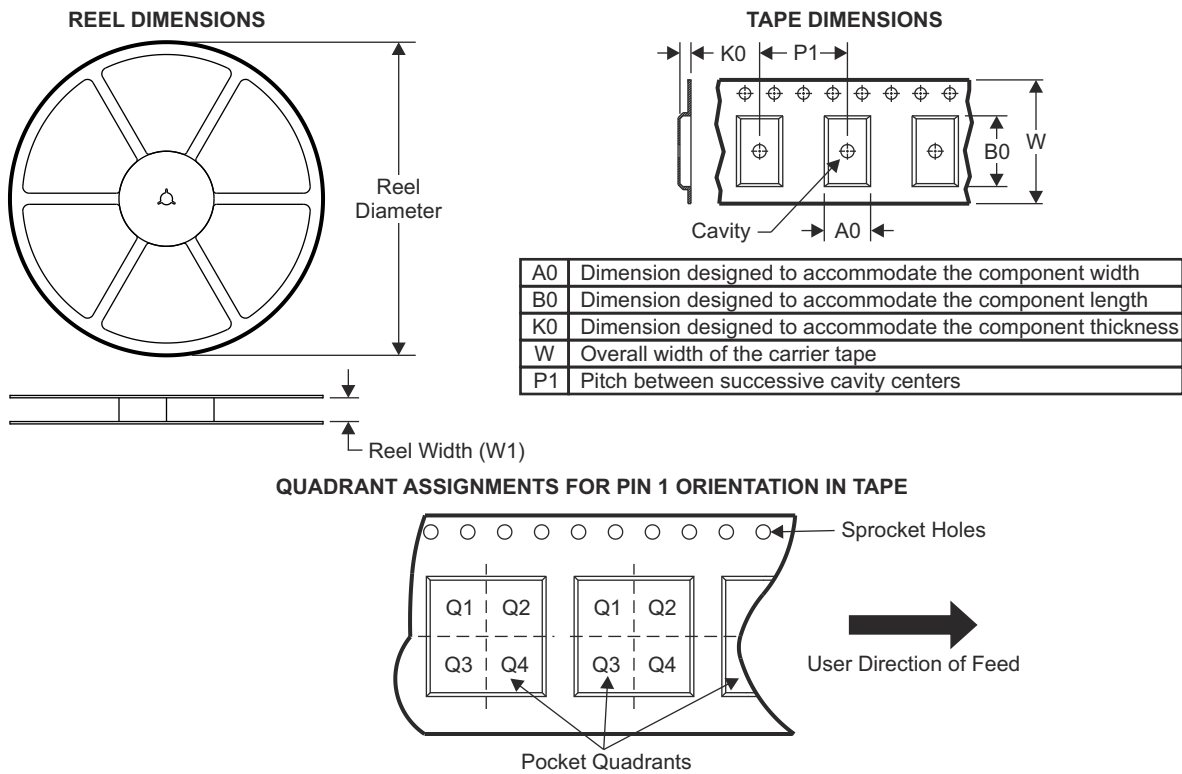
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (April 2024) to Revision A (July 2024)	Page
• Changed the document status from Advanced Information to Production Data.....	1

11 Mechanical, Packaging, and Orderable Information

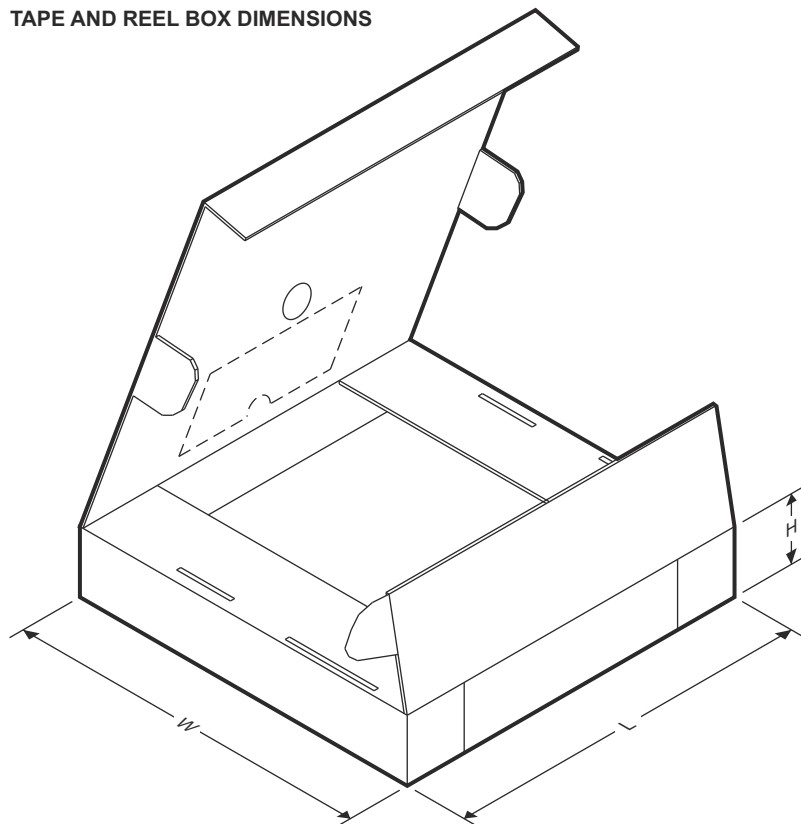
The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

11.1 Tape and Reel Information



Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN4599DBVRQ1	SOT-23	DBV	6	3000	178	9	2.4	2.5	1.2	4	8	Q3

TAPE AND REEL BOX DIMENSIONS

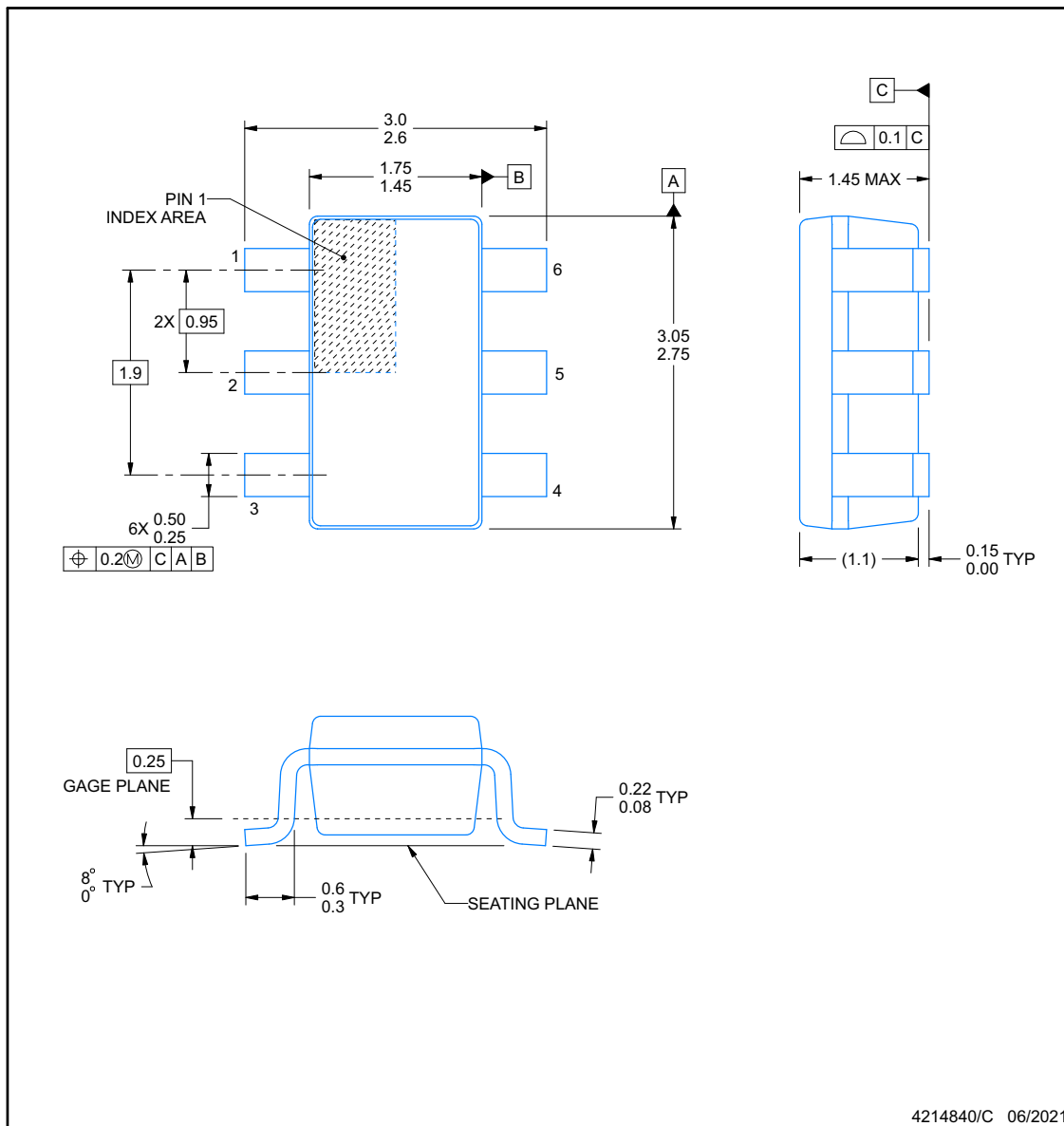


Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN4599DBVRQ1	SOT-23	DBV	6	3000	180	180	18

11.2 Mechanical Data

**DBV0006A**
PACKAGE OUTLINE
SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR

**NOTES:**

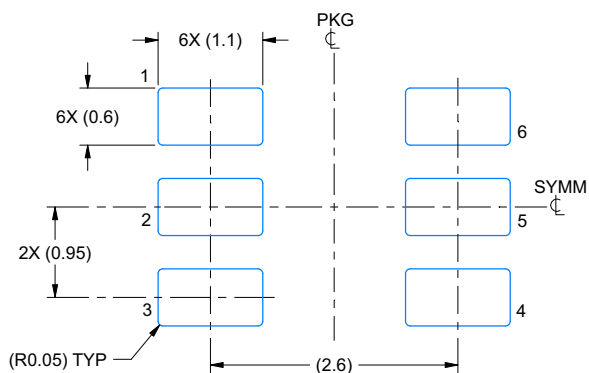
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.
4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
5. Reference JEDEC MO-178.

EXAMPLE BOARD LAYOUT

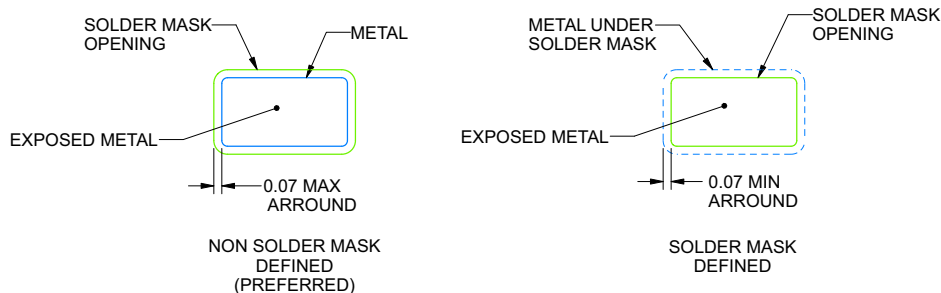
DBV0006A

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:15X



SOLDER MASK DETAILS

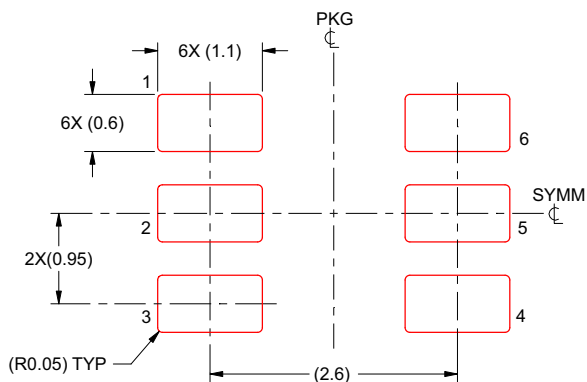
4214840/C 06/2021

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN**DBV0006A****SOT-23 - 1.45 mm max height**

SMALL OUTLINE TRANSISTOR



SOLDER PASTE EXAMPLE
 BASED ON 0.125 mm THICK STENCIL
 SCALE:15X

4214840/C 06/2021

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
SN4599DBVRQ1	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	3GTT
SN4599DBVRQ1.A	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	3GTT

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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